SMD Characterization Using Progressive De-embedding Methods with a VNA

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A principle challenge in performing measurements is to accurately remove the effects of the test fixture. Copper Mountain Technologies presents a simplified way to automatically remove the fixture effects to characterize SMD components using advanced algorithms with a Vector Network Analyzer. CMT's Automatic Fixture Removal (AFR) VNA software plug-in enables the measurement of a wide range of components through comprehensive methods tailored to specific fixture properties. The intuitive AFR software plug-in moves the calibration plane towards hard to access DUTs and guides the de-embedding process using either time-gating, filtering, or bisect methods. These methods provide the user with better measurement accuracy and reliability based on the components to test.